

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Attorney Docket No. UCF-306DIV (which is a divisional of application SN: 10/082,658 filed 10/19/2001 which claims priority of SN: 09/881,620 filed June 14, 2001 and U. S. Provisional application 60/242,102 filed October 20, 2000)

Serial No.: 09/____

Filed: ____/____/____

Divisional Application of Serial No.: 10/082,658

Filed: 10/19/2001

First Named Inventor: Martin Richardson

For: EUV, XUV, AND X-RAY WAVELENGTH SOURCES CREATED FROM LASER PLASMA PRODUCED FROM LIQUID METAL SOLUTIONS,
AND NANO-SIZE PARTICLES IN SOLUTIONS

Examiner: COURTNEY D. THOMAS

Group: 2882

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents
and Trademarks
P O Box 1450
Alexandria, VA 22313-1450


Sir:

Pursuant to 37 CFR §§ 1.97 and 1.98, record is being made below in a form PTO-1449 of documents which the Patent Office may wish to consider in connection with examination of the above-identified patent application. It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in this case. As provided in § 1.97(g), no representation is made or intended that a thorough art search was made. As provided in 37 C.F.R. § 1.97(h), this Supplemental Information Disclosure Statement does not constitute an admission of any kind, and specifically is not an admission that the documents listed on the attached PCT-1449 are, or are considered to be, material to the patentability of the above-identified patent application, as defined in 37 C.F.R. § 1.56(b).

Copies of the cited references were previously submitted to the USPTO in the parent application No.: 10/082,658 filed 10/19/2001 and 09/881,620 filed June 14, 2001 and made of record. Applicants claim priority to said application under 35 U. S. C. § 120. Accordingly, copies of those documents are not provided with this Statement pursuant to 37 CFR § 1.98(d).

It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in the case.

Respectfully submitted,



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US DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

APPLICANT: MARTIN RICHARDSON

FOR: EUV, XUV, AND X-RAY WAVELENGTH SOURCES CREATED FROM LASER PLASMA
PRODUCED FROM LIQUID METAL SOLUTIONS, AND NANO-SIZE PARTICLES IN SOLUTION

LIST OF ART CITED BY APPLICANT

U.S. PATENT DOCUMENTS

	EXAMINER	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
CT 							

J1050 U.S. PTO
10/082658
10/19/01

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OA T.P. Donaldson, *SOFT X-RAY SPECTROSCOPY OF LASER-PRODUCED PLASMAS WITH A CONVEX MICA CRYSTAL SPECTROMETER*, X-Ray Astronomy Group, Vol. 9, P. 1645-1655, 1 March 1976

OB T. Mochizuki, *SOFT X-RAY OPTICS AND TECHNOLOGY*, Proceedings Of SPIE-The International Society For Optical Engineering, Vol. 733, P. 23-27, December 1986

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OD W.T. Silfvast, *LASER-PRODUCED PLASMAS FOR X-RAY PROJECTION LITHOGRAPHY*, American Vacuum Society, P. 3126-3133, 4 August 1992

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Courtney Thomas

01.02.03

Notice of References Cited	Application/Control No. 10/082,658	Applicant(s)/Patent Under Reexamination RICHARDSON, MARTIN	
	Examiner Courtney Thomas	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,307,913	10-2001	Foster et al.	378/34
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	Examiner Courtney Thomas		Art Unit 2882	Page 1 of 1

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*	B	US-5,577,091	11-1996	Richardson et al.	378/119
*	C	US-6,307,913	10-2001	Foster et al.	378/34
	D	US-			
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